DATA SHEET 74LVT573 3.3V Octal D-type transparent latch (3-State)

INTEGRATED CIRCUITS

Product specification Supersedes data of 1995 Nov 14 IC23 Data Handbook 1998 Feb 19







74LVT573

FEATURES

- Inputs and outputs on opposite side of package allow easy interface to microprocessors
- 3-State output buffers
- Common output enable
- TTL input and output switching levels
- Input and output interface capability to systems at 5V supply
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion/extraction permitted
- No bus current loading when output is tied to 5V bus
- Latch-up protection exceeds 500mA per JEDEC Std 17
- Power-up 3-State
- Power-up reset
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200V per Machine Model

QUICK REFERENCE DATA

DESCRIPTION

The LVT573 is a high-performance BiCMOS product designed for VCC operation at 3.3V. This device is an octal transparent latch coupled to eight 3-State output buffers. The two sections of the device are controlled independently by Enable (E) and Output Enable (\overline{OE}) control gates. The 74LVT573 has a broadside pinout configuration to facilitate PC board layout and allow easy interface with microprocessors.

The data on the D inputs are transferred to the latch outputs when the Latch Enable (E) input is High. The latch remains transparent to the data inputs while E is High, and stores the data that is present one setup time before the High-to-Low enable transition.

The 3-State output buffers are designed to drive heavily loaded 3-State buses, MOS memories, or MOS microprocessors. The active-Low Output Enable (\overline{OE}) controls all eight 3-State buffers independent of the latch operation.

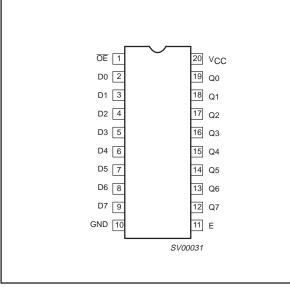
When \overline{OE} is Low, the latched or transparent data appears at the outputs. When \overline{OE} is High, the outputs are in the High-impedance "OFF" state, which means they will neither drive nor load the bus.

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25°C; GND = 0V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay Dn to Qn	C _L = 50pF; V _{CC} = 3.3V	2.5 2.7	ns
C _{IN}	Input capacitance	$V_{I} = 0V \text{ or } 3.0V$	4	pF
C _{OUT}	Output capacitance	Outputs disabled; $V_0 = 0V$ or 3.0V	8	pF
I _{CCZ}	Total supply current	Outputs disabled; $V_{CC} = 3.6V$.13	mA

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
20-Pin Plastic SOL	-40°C to +85°C	74LVT573 D	74LVT573 D	SOT163-1
20-Pin Plastic SSOP Type II	-40°C to +85°C	74LVT573 DB	74LVT573 DB	SOT339-1
20-Pin Plastic TSSOP Type I	-40°C to +85°C	74LVT573 PW	74LVT573PW DH	SOT360-1

PIN CONFIGURATION



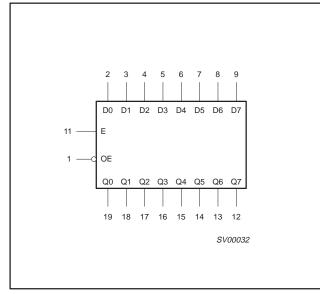
PIN DESCRIPTION

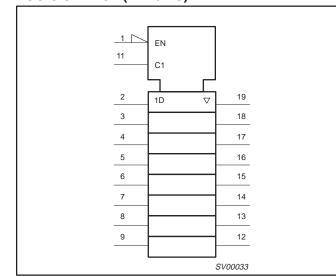
PIN NUMBER	SYMBOL	FUNCTION
1	ŌĒ	Output enable input (active-Low)
2, 3, 4, 5, 6, 7, 8, 9	D0-D7	Data inputs
19, 18, 17, 16, 15, 14, 13, 12	Q0-Q7	Data outputs
11	E	Enable input (active-High)
10	GND	Ground (0V)
20	V _{CC}	Positive supply voltage

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LOGIC SYMBOL





FUNCTION TABLE

	INPUTS		INTERNAL	OUTPUTS	OPERATING MODE
ŌĒ	E	Dn	REGISTER	Q0 – Q7	OPERATING MODE
L	H H	L H	L H	L H	Enable and read register
L	${\rightarrow} \rightarrow$	l h	L H	L H	Latch and read register
L	L	Х	NC	NC	Hold
Н	Х	Х	NC	Z	Disable outputs

H = High voltage level h = High voltage level one set-up time prior to the High-to-Low E transition

Low voltage level L =

Low voltage level one set-up time prior to the High-to-Low E transition 1 =

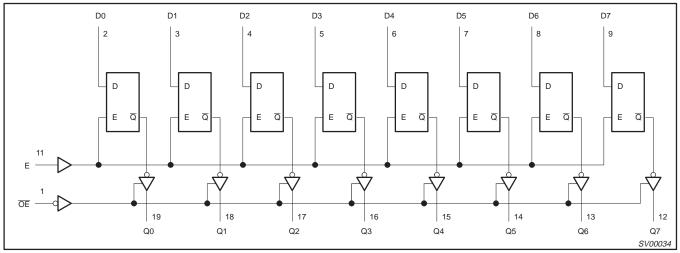
NC= No change

X = Don't care

High impedance "off" state High-to-Low E transition Ζ =

 $\overline{\downarrow}$ =

LOGIC DIAGRAM



LOGIC SYMBOL (IEEE/IEC)

74LVT573

ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +4.6	V
I _{IK}	DC input diode current	V ₁ < 0	-50	mA
VI	DC input voltage ³		-0.5 to +7.0	V
Ι _{ΟΚ}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	Output in Off or High state	-0.5 to +7.0	V
		Output in Low state	128	~ ^
IOUT	DC output current	Output in High state	-64	mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction

2. temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C. 3. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS		UNIT
STWBUL	PARAMETER	MIN	MAX	UNIT
V _{CC}	DC supply voltage	2.7	3.6	V
VI	Input voltage	0	5.5	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Input voltage		0.8	V
I _{ОН}	High-level output current		-32	mA
	Low-level output current		32	mA
I _{OL}	Low-level output current; current duty cycle \leq 50%, f \geq 1kHz		64	ma
$\Delta t/\Delta v$	Input transition rise or fall rate; outputs enabled		10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

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LIMITS SYMBOL **TEST CONDITIONS** Temp = -40° C to $+85^{\circ}$ C UNIT PARAMETER MIN TYP¹ MAX V $V_{CC} = 2.7V; I_{IK} = -18mA$ VIK Input clamp voltage -0.9-1.2 $V_{CC} = 2.7$ to 3.6V; $I_{OH} = -100\mu A$ V_{CC}-0.1 V_{CC}-0.2 V_{CC} = 2.7V; I_{OH} = -8mA 2.5 V VOH High-level output voltage 2.4 V_{CC} = 3.0V; I_{OH} = -32mA 2.0 2.2 $V_{CC} = 2.7 V; I_{OL} = 100 \mu A$ 0.1 0.2 $V_{CC} = 2.7V; I_{OL} = 24mA$ 0.3 0.5 V_{CC} = 3.0V; I_{OL} = 16mA 0.25 0.4 V VOL Low-level output voltage V_{CC} = 3.0V; I_{OL} = 32mA 0.3 0.5 0.55 V_{CC} = 3.0V; I_{OL} = 64mA 0.4 V Power-up output low voltage⁵ $V_{CC} = 3.6V$; $I_O = 1mA$; $V_I = GND$ or V_{CC} 0.13 0.55 V_{RST} $V_{CC} = 0 \text{ or } 3.6 \text{V}; \text{ V}_{I} = 5.5 \text{V}$ 1 10 $V_{CC} = 3.6V; V_I = V_{CC} \text{ or } GND$ Control pins ±0.1 ±1 Input leakage current uΑ II. $V_{CC} = 3.6V; V_{I} = V_{CC}$ 0.1 1 Data pins⁴ $V_{CC} = 3.6V; V_I = 0$ -1 -5 1 ±100 Output off current $V_{CC} = 0V; V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5V$ **I**OFF μΑ $V_{CC} = 3V; V_{I} = 0.8V$ 75 150 $V_{CC} = 3V; V_1 = 2.0V$ -75 -150 Bus Hold current A inputs⁷ uΑ Іноі п ±500 $V_{CC} = 0V$ to 3.6V; $V_{CC} = 3.6V$ Current into an output in the $V_{O} = 5.5V; V_{CC} = 3.0V$ 125 IEX 60 μΑ High state when $V_O > V_{CC}$ Power up/down 3-State output $V_{CC} \le 1.2V$; $V_O = 0.5V$ to V_{CC} ; $V_I = GND$ or V_{CC} ; μΑ 1 ±100 I_{PU/PD} OE/OE = Don't carecurrent³ IOZH 3-State output High current V_{CC} = 3.6V; V_{O} = 3V; V_{I} = V_{IL} or V_{IH} 1 5 μΑ $V_{CC} = 3.6V; V_{O} = 0.5V; V_{I} = V_{IL} \text{ or } V_{IH}$ -1 -5 3-State output Low current IOZL $V_{CC} = 3.6V$; Outputs High, $V_I = GND$ or V_{CC} . $I_O = 0$ 0.13 0.19 ICCH Quiescent supply current $V_{CC} = 3.6V$; Outputs Low, $V_I = GND$ or V_{CC} . $I_O = 0$ 3 12 I_{CCL} mΑ $V_{CC} = 3.6V$; Outputs Disabled; $V_I = GND$ or V_{CC} , $I_O = 0^5$ 0.13 0.19 I_{CCZ} Additional supply current per $V_{CC} = 3V$ to 3.6V; One input at V_{CC} -0.6V, 0.2 ΔI_{CC} 0.1 mΑ input pin² Other inputs at V_{CC} or GND

DC ELECTRICAL CHARACTERISTICS

NOTES:

1. All typical values are at $V_{CC} = 3.3V$ and $T_{amb} = 25^{\circ}C$. 2. This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND

3. This parameter is valid for any V_{CC} between 0V and 1.2V with a transition time of up to 10msec. From V_{CC} = 1.2V to V_{CC} = $3.3V \pm 0.3V$ a transition time of 100 μ sec is permitted. This parameter is valid for T_{amb} = 25°C only

4. Unused pins at V_{CC} or GND.

6. I_{CCZ} is measured with outputs pulled to V_{CC} or GND.

^{5.} For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.

^{7.} This is the bus hold overdrive current required to force the input to the opposite logic state.

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AC CHARACTERISTICS

GND = 0V, $t_R = t_F = 2.5ns$, $C_L = 50pF$, $R_L = 500\Omega$; $T_{amb} = -40^{\circ}C$ to $+85^{\circ}C$.

				L	IMITS		
SYMBOL	PARAMETER	WAVEFORM	Vc	_C = 3.3V ± 0	.3V	V _{CC} = 2.7V	UNIT
			MIN	TYP ¹	MAX	MAX	
t _{PLH} t _{PHL}	Propagation delay Dn to Qn	2	1.0 1.0	2.5 2.7	4.2 4.3	4.7 5.2	ns
t _{PLH} t _{PHL}	Propagation delay E to Qn	1	1.6 2.5	3.5 4.3	5.6 6.5	6.3 7.2	ns
t _{PZH} t _{PZL}	Output enable time to High and Low level	4 5	1.0 1.3	2.8 3.3	5.1 5.5	6.2 6.6	ns
t _{PHZ} t _{PLZ}	Output disable time from High and Low level	4 5	2.0 1.5	3.7 3.0	5.7 4.6	6.7 5.1	ns

NOTE:

1. All typical values are at V_{CC} = 3.3V and T_{amb} = 25°C.

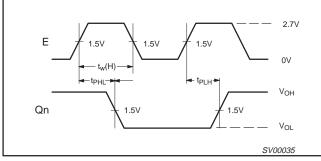
AC SETUP REQUIREMENTS

GND = 0V, $t_R = t_F = 2.5ns$, $C_L = 50pF$, $R_L = 500\Omega$; $T_{amb} = -40^{\circ}C$ to +85°C.

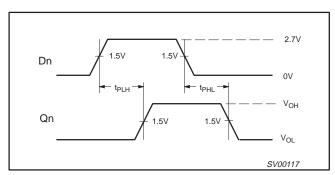
				LIMITS	3	
SYMBOL	PARAMETER	WAVEFORM	V _{CC} = 3.	$3V \pm 0.3V$	$V_{CC} = 2.7V$	UNIT
			MIN	MAX	MIN	
t _S (H) t _S (L)	Setup time, High or Low, Dn to E	3	0.7 0.7		0.6 0.6	ns
T _H (H) T _H (L)	Hold time, High or Low, Dn to E	3	1.6 1.6		1.8 1.8	ns
T _W (H)	E pulse width High	1	3.3		3.3	ns

AC WAVEFORMS

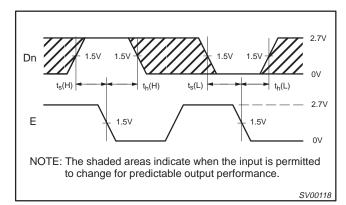
 V_{M} = 1.5V, V_{IN} = GND to 2.7V



Waveform 1. Propagation Delay, Enable to Output, and Enable Pulse Width



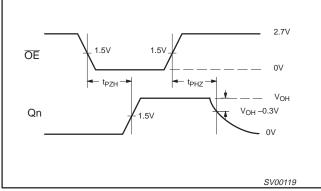




Waveform 3. Data Setup and Hold Times

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Waveform 4. 3-State Output Enable Time to High Level and **Output Disable Time from High Level**

TEST CIRCUIT AND WAVEFORM

PULSE GENERATOR

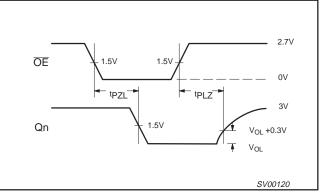
TEST

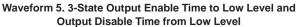
t_{PLH}/t_{PHL}

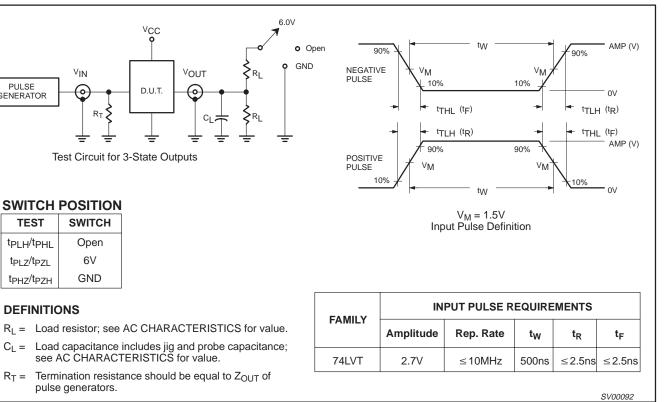
t_{PLZ}/t_{PZL}

t_{PHZ}/t_{PZH}

R_T =

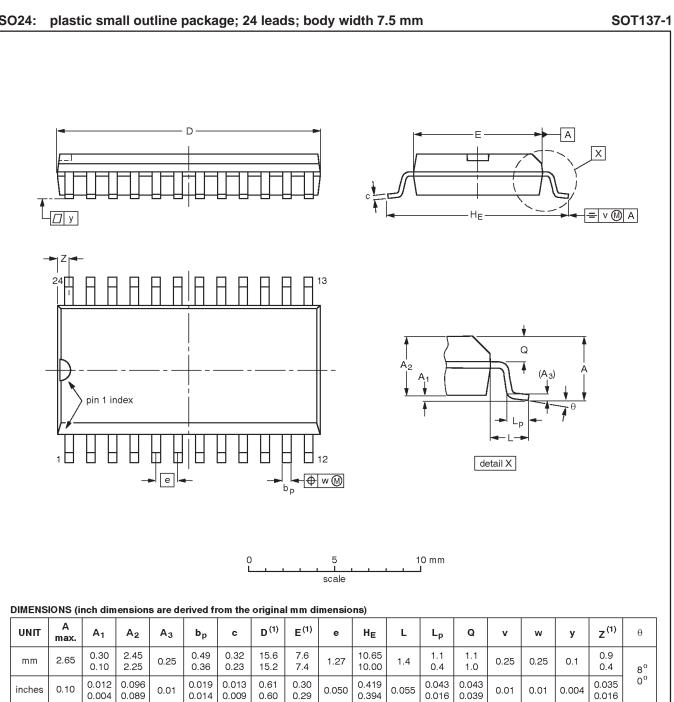






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SO24:

Note

0.004

0.089

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

0.014

0.009

0.60

0.29

VERSION FROM FROM FROM FROM FROM FROM FROM FROM	ISSUE DATE	
VERSION IEC JEDEC EIAJ PROJECTION	ISSUE DATE	
SOT137-1 075E05 MS-013AD	-95-01-24 97-05-22	

0.394

0.016

0.039

OUTLINE

VERSION

SOT340-1

IEC

JEDEC

MO-150AG

74LVT573

ISSUE DATE

93-09-08

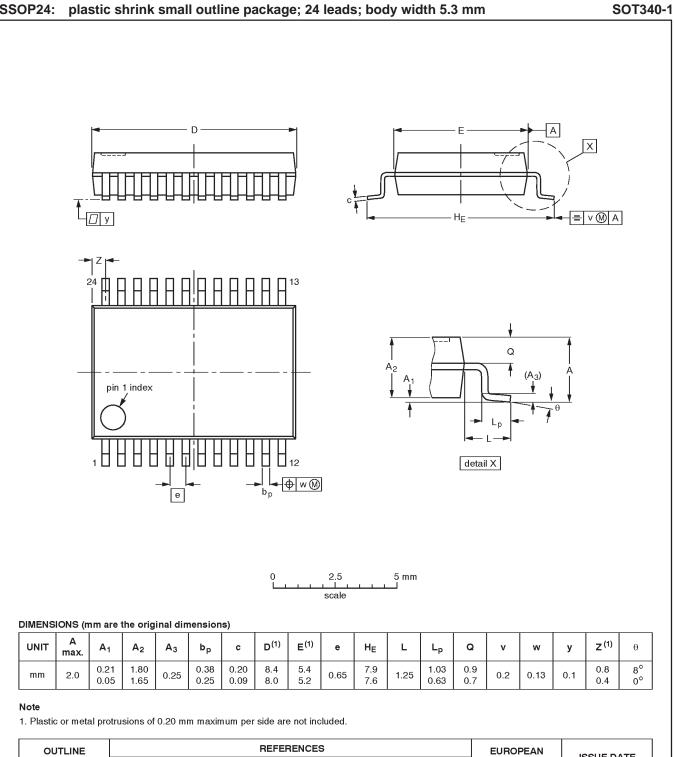
95-02-04

PROJECTION

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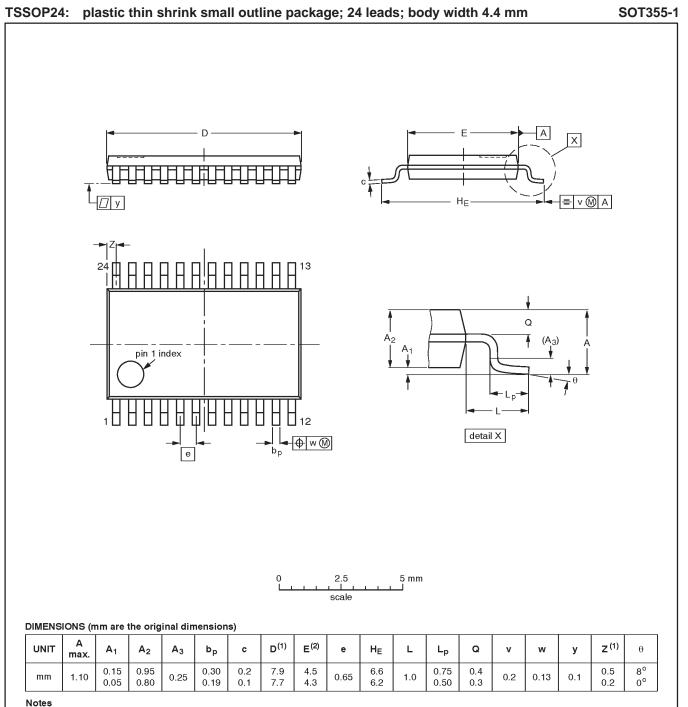
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EIAJ

SSOP24:	plastic shrink small outline package; 24 leads; body width 5.3 mm	
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1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFERENCES			EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT355-1		MO-153AD				-93-06-16- 95-02-04

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NOTES

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Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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